ASAHI KASEI MICRODEVICES

EQ-430L

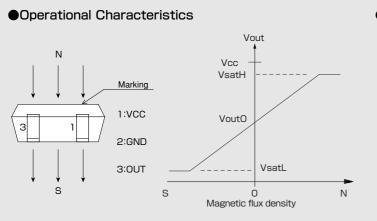
Shipped in packet-tape reel(5000pcs/Reel)

EQ-430L is composed of an InAs Quantum Well Hall Element and a signal processing IC chip in a package Notice: It is requested to read and accept "IMPORTANT NOTICE" written on the back of the front cover of this catalogue.

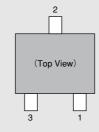
Features

- Analog output which proportional to the magnetic field strength and pole.
- Magnetic sensitivity 130mV/mT(typ.)
- Supply voltage from 3.0V to 5.5V at single power supply
- Operating temperature range -40°C~100°C
- Ratio-metric analog output
- 3pin surface mount plastic package
- Quick response 4 μ s
- (when the rise-up time of magnetic field is rather than $1 \mu s$)
- Low output noise voltage 10mVp-p



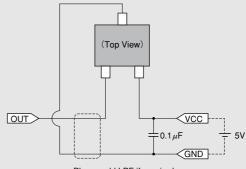


Pin and functions



Pin No.	Pin name	Function
1	VCC	Power supply
2	GND	Ground
3	OUT	Output

Application Circuit

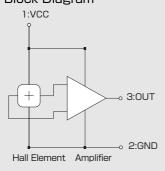


Please add LPF if required.

Recommend operating conditions

parameter	symbol	min	typ	max	unit
Supply voltage	Vcc	3.0	5.0	5.5	V
output current	Іоит	-1.0		1.0	mA
output load	CL			1000	pF

Functional Block Diagram



●Absolute Maximum Ratings (Ta=25°C)

parameter	symbol	specification	unit
Supply voltage	V _{CC}	$-0.3 \sim 6$	V
output current	Iout	±1.2 ^(*)	mA
operating ambient temperature	Topr	<i>−</i> 40 ~ 100	°C
Storage ambient temperature	Tstg	-40 ~ 125	Ĵ

(*) Vcc=5V

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Electric characteristics (TA=25°C, Vcc=5V)

Parameter	Symbol	Conditions	min	Тур	Max	Unit
Current consumption	Icc	B=0mT with no load		9	12	mA
Output saturation voltage at High Level ^(*1)	V _{SATH}	I _{OUT} =-1mA	V _{CC} -0.3		V _{CC}	V
Output saturation voltage at Low Level ^(*1)	V _{SATL}	I _{OUT} =1mA	0		0.3	V
Bandwidth ^(*2)	f _T	-3dB C _L =1000pF		70		kHz
Response time ^(*2)	t _{RES}	Rise time : 10% of Input MFD to 90% of output voltage. Fall time: 90% of Input MFD to 10% of output voltage. (under input/output MFD step is 1 to 2μ s) CL=1000pF		4		μs
Output rise time ^(*2)	t _{RISE}	10% to 90% of output voltage under input/output MFD step is 1 to 2μ s. C _L =1000pF		-		
Output fall time ^(*2)	t _{FALL}	90% to 10% of output voltage under input/output MFD step is 1 to 2μ s C _L =1000pF		5		μs
Output delay time ^(*2)	^t REAC	Rise time : 10% of Input MFD to 10% of output voltage. Fall time: 90% of Input MFD to 90% of output voltage. (under input/output MFD step is 1 to 2μ s) CL=1000pF		0.3		μs
Output noise voltage ^(*2)	V _{Np-p}			10		mVp-p
(*182) Design target at 25°C				10	×1mT	10Gauss

%1mT = 10Gauss

(*1&2) Design target at 25°C

Magnetic characteristics (TA=25°C, Vcc=5V)

Parameter	Symbol	Conditions	min	Тур	Max	Unit
Sensitivity ^(*3)	V _h	B=0、±11mT with no load	110	130	150	mV/mT
Quiescent voltage	V _{OUT0}	B=0mT	2.3	2.5	2.7	V
Linearity ^(*4)	ρ	B=0mT (I _{OUT} =0mA)	-0.5	0.5	0.5	%F.S.
		$B=\pm 13mT (I_{OUT}=\pm 1mA)$				

(*3) See Characteristic Definitions section

(*4) See Characteristic Definitions section

Characteristic Definitions

①Magnetic sensitivity Vh (mV/mT)

Magnetic sensitivity is defined as the slope of the straight line obtained from three points, Quiescent voltage Vouto, Vout (+B), Vout (-B) (B is described in measurement condition), by the least square approximation.

②Linearity ρ (%F.S.)

Linearity is defined as the ratio of a error voltage against FULLSCALE. Where error voltage is calculate as the difference from the straight line obtained from three points, Quiescent voltage Vouto, Vout (+B), Vout (-B) (B and Output current are described in measurement condition shown below), by the least square approximation.

- $\langle Condition \rangle$:0mT applied, lout = 0mA
- +BmT applied : IOUT=+1.0mA (Draw out from output)

$$-BmT \text{ applied : Iout} = -1.0mA (Draw in to output)$$

$$\rho = \frac{V_{out}(B) - \{V_h \times B + V_{int}\}}{V_{out}(B) - \{V_h \times B + V_{int}\}} \times 100$$

$$= \frac{1}{V_{out}(+B) - V_{out}(-B)} \times 10$$

Where FULLSCALE(F.S.) is defied as Vout (+B), Vout (-B), Vint is y-intercepts of the line obtained in the Definition of Magnetic sensitivity.

③Error in Ratiometric of Magnetic sensitivity and Error in Ratiometric of quiescent voltage

Error in ratiometric is defined as the ratio of the variation of sensitivity and guiescent voltage at 3V and 5V as following equations..

$$V_{h-R} = \frac{\frac{V_{h}(V_{CC}=3V)}{V_{h}(V_{CC}=5V)} - \frac{3}{5}}{\frac{3}{5}} \times 100 \quad V_{OUT0-R} = \frac{\frac{V_{OUT0}(V_{CC}=3V)}{V_{OUT0}(V_{CC}=5V)} - \frac{3}{5}}{\frac{3}{5}} \times 100$$

%1mT = 10Gauss

●Ratio-metric characteristics (TA=25℃)

Parameter	Symbol	Conditions	min	Тур	Max	Unit
Error in Ratiometric of Magnetic sensitivity ^(*5)	V _{h-R}	B=0 \pm 11mT with no load	-3		3	%
Error in Ratiometric of Quiescent voltage ^(*5)	V _{OUT0-R}	B=0mT	-3		3	%

(*5) See Characteristic Definitions section

%1mT = 10Gauss

(4) Response time $t_{RES}(\mu s)$

Response time is defined as the time from the 90% reach point of input magnetic field rise up to the 90% reach point of output voltage rise up

(5)Output rise time, Output fall time trise, trall (μ s)

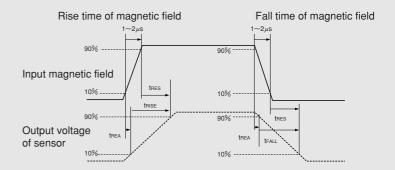
Output rise up time is defined as the time from the 10% point to the 90% point of output voltage under a pulse like magnetic field input shown below.

Output fall down time is defined as the time from the 90% point to the 10% point of output voltage under a pulse like magnetic field input shown below.

(6) Output delay time $\text{treac}(\mu s)$

Output delay time is defined as the time from the 10% point in rise up(90% point in fall down) of input magnetic field to the 10% point in rise up(90% point in fall down) of output voltage under a pulse like magnetic field input shown below..

Relations of the input Magnetic field and tres_trise_trall, treac



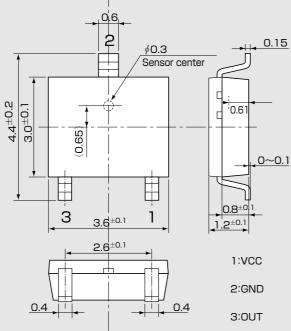
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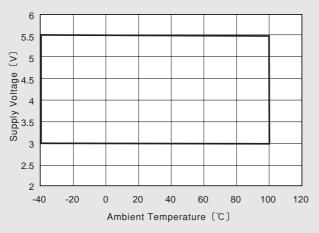
•This product contains galium arsenide(GaAs).Handling and discarding precsutions required.

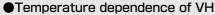
Package (Unit:mm)

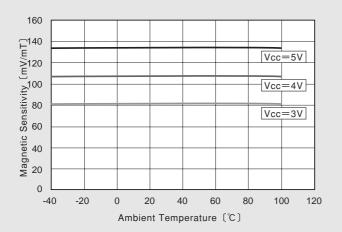


%The sensor senter is located within the ϕ 0.3mm circle.

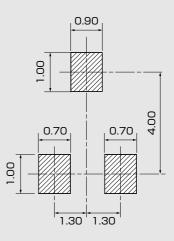
Supply Voltage



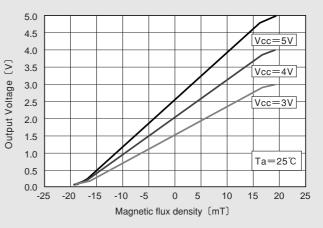


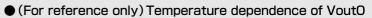


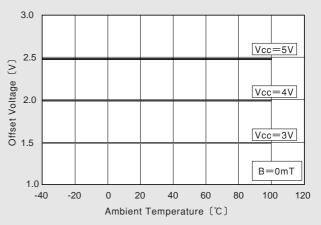
●(For reference only)Land Pattern (Unit:mm)



Operational Characteristics







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